TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

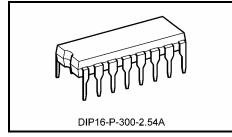
# **TC4521BP**

### TC4521BP 24-Stage Frequency Divider

TC4521BP is frequency divider consisting of 24 stages of flip-flop. The input section is equipped with an inverter to enable to use either RC oscillator circuit or crystal oscillator circuit and to accept pulse from external clock source.

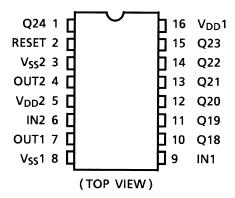
Each flip-flop is inverted by the falling edge of the output of previous stage flip-flop and this can count up to the maximum of  $2^{24} = 16,777,216$ .

Since six outputs,  $2^{18}$ ,  $2^{19}$ ,  $2^{20}$ ,  $2^{21}$ ,  $2^{22}$ , and  $2^{23}$  are available besides of  $2^{24}$ , adjustment of frequency divided output can be achieved.



Weight: 1.00 g (typ.)

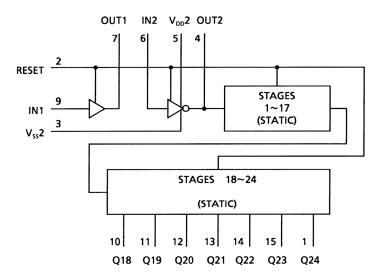
### Pin Assignment



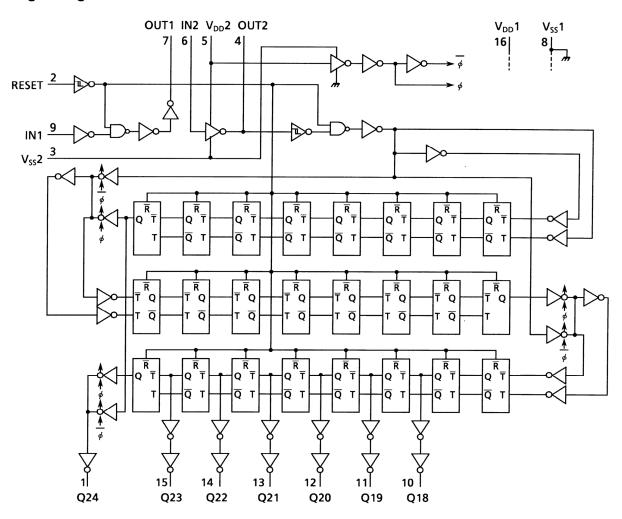
### **Count Capacity**

Output	Count Capacity			
Q18	$2^{18} = 262,144$			
Q19	$2^{19} = 524,288$			
Q20	$2^{20} = 1,048,576$			
Q21	$2^{21} = 2,097,152$			
Q22	$2^{22} = 4,194,304$			
Q23	$2^{23} = 8,388,608$			
Q24	$2^{24} = 16,777,216$			

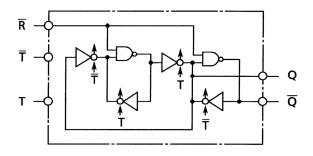
# **Block Diagram**



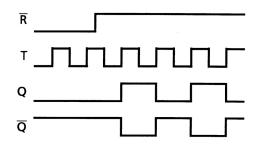
# **Logic Diagram**



# **Internal Flip Flop Logic Diagram**



### **Flip Flop Timing Chart**



### **Absolute Maximum Ratings (Note)**

Characteristics	Symbol Rating		Unit
DC supply voltage	V <sub>DD</sub> 1	V <sub>SS</sub> 1 - 0.5~V <sub>SS</sub> 1 + 20	V
DC supply voltage	V <sub>DD</sub> 2	V <sub>SS</sub> 1 - 0.5~V <sub>DD</sub> 1 + 0.5	V
Input voltage	V <sub>IN</sub>	V <sub>SS</sub> 1 - 0.5~V <sub>DD</sub> 1 + 0.5	V
Output voltage	V <sub>OUT</sub>	V <sub>SS</sub> 1 - 0.5~V <sub>DD</sub> 1 + 0.5	V
DC input current	I <sub>IN</sub>	±10	mA
Power dissipation	PD	300	mW
Operating temperature range	T <sub>opr</sub>	-40~85	°C
Storage temperature range	T <sub>stg</sub>	-65~150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

# Operating Ranges (V<sub>SS</sub>1 = V<sub>SS</sub>2 = 0 V) (Note)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
DC supply voltage	V <sub>DD</sub> 1, V <sub>DD</sub> 2	_	3	_	18	V
Input voltage	V <sub>IN</sub>		0	_	V <sub>DD</sub> 1	V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{DD}$  or  $V_{SS}$ .

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# Static Electrical Characteristics (V\_{SS}1 = V\_{SS}2 = 0 V, V\_{DD}1 = V\_{DD}2)

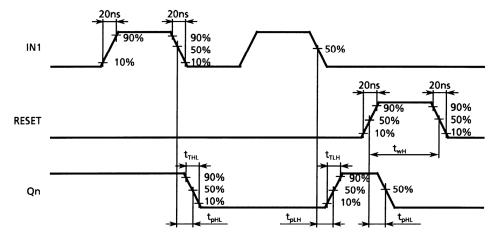
S		Svm-	Sym- Test Condition		-40°C		25°C			85°C		
Charac	teristics	bol		V <sub>DD</sub> (V)	Min	Max	Min	Тур.	Max	Min	Max	Unit
				5	4.95	_	4.95	5.00	_	4.95	_	
High-level voltage	output	$V_{OH}$	I <sub>OUT</sub>   < 1 μA	10	9.95	_	9.95	10.00	_	9.95	_	V
			$V_{IN} = V_{SS}, V_{DD}$	15	14.95	_	14.95	15.00	_	14.95	_	
			I <sub>OUT</sub>   < 1 μA	5	_	0.05	_	0.00	0.05	_	0.05	
Low-level of voltage	output	$V_{OL}$		10	_	0.05	_	0.00	0.05	_	0.05	V
ranaga			$V_{IN} = V_{SS}, V_{DD}$	15	_	0.05	_	0.00	0.05	_	0.05	
			V <sub>OH</sub> = 4.6 V	5	-0.61	_	-0.51	-1.0	_	-0.42	_	
			V <sub>OH</sub> = 2.5 V	5	-2.5	_	-2.1	-4.0	_	-1.7	_	
Output hig	h current	loh	V <sub>OH</sub> = 9.5 V	10	-1.5	_	-1.3	-2.2	_	-1.1	_	mA
			V <sub>OH</sub> = 13.5 V	15	-4.0	_	-3.4	-9.0	_	-2.8	_	
			$V_{IN} = V_{SS}, V_{DD}$									
			V <sub>OL</sub> = 0.4 V	5	0.61	_	0.51	1.2	_	0.42	_	
Output low current	l <sub>OL</sub>	$V_{OL} = 0.5 V$	10	1.5	_	1.3	3.2	_	1.1	_	mA	
		V <sub>OL</sub> = 1.5 V	15	4.0	_	3.4	12.0	_	2.8	_		
		$V_{IN} = V_{SS}, V_{DD}$										
			$V_{OUT} = 0.5 \text{ V}, 4.5 \text{ V}$	5	3.5	_	3.5	2.75	_	3.5	_	
Input high	voltago	ViH	V <sub>OUT</sub> = 1.0 V, 9.0 V	10	7.0	_	7.0	5.5	_	7.0	_	V
input nign	Input high voltage		V <sub>OUT</sub> = 1.5 V, 13.5 V	15	11.0	_	11.0	8.25	_	11.0	_	٧
			I <sub>OUT</sub>   < 1 μA									
			V <sub>OUT</sub> = 0.5 V, 4.5 V	5	_	1.5	_	2.25	1.5	_	1.5	
la acut la cocc			V <sub>OUT</sub> = 1.0 V, 9.0 V	10	_	3.0	_	4.5	3.0		3.0	,
Input low voltage	VIL	V <sub>OUT</sub> = 1.5 V, 13.5 V	15	_	4.0	_	6.75	4.0	_	4.0	V	
			$ I_{OUT}  < 1 \mu A$									
Input "H"	"H" level	Ι <sub>ΙΗ</sub>	V <sub>IH</sub> = 18 V	18		0.1		10 <sup>-5</sup>	0.1	_	1.0	^
current	"L" level	I <sub>IL</sub>	$V_{IL} = 0 V$	18	_	-0.1	_	-10 <sup>-5</sup>	-0.1		-1.0	μΑ
			V V V	5	_	5	_	0.005	5	_	150	
Quiescent current	supply	I <sub>DD</sub>	$V_{IN} = V_{SS}, V_{DD}$	10	_	10	_	0.010	10	_	300	μΑ
Current			(Note)	15	_	20	_	0.015	20	_	600	

Note: All valid input combinations.

# Dynamic Electrical Characteristics (Ta = 25°C, $V_{SS}1 = V_{SS}2 = 0$ V, $V_{DD}1 = V_{DD}2$ , $C_L = 50$ pF)

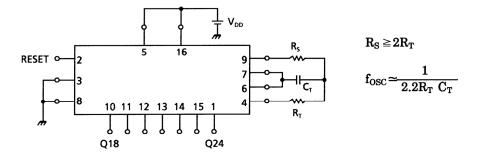
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit	
5.16.165.165	Cy20.		V <sub>DD</sub> (V)	141111	1 ) [7]	Max	Onic
Output transition time			5	_	70	200	
(low to high)	t <sub>TLH</sub>	_	10	_	35	100	ns
(low to high)			15	_	30	80	
Output transition time			5	_	70	200	
(high to low)	t <sub>THL</sub>	_	10	_	35	100	ns
(riigit to low)			15	_	30	80	
Propagation delay time	t <sub>pLH</sub>		5	_	1.1	9.0	
(IN2-Q18)	t <sub>pHL</sub>	_	10	_	0.5	3.5	μS
(1142 @ 10)	фпь		15	_	0.3	2.7	
Propagation delay time	t <sub>pLH</sub>		5	_	1.4	12	
(IN2-Q24)	t <sub>pHL</sub>	_	10	_	0.6	4.5	μS
(1112 921)	фпь		15	_	0.4	3.5	
Propagation delay time			5	_	220	2600	
(RESET-Qn)	t <sub>pHL</sub>	_	10	_	100	1000	ns
(NEOLI WII)			15	_	70	750	
			5	3	9.5	_	
Max clock frequency	$f_{CL}$	_	10	6	17.5	_	MHz
			15	8	23.5	_	
Max clock input rise time	t <sub>rCL</sub>		5				
Max clock input fall time	t <sub>fCL</sub>	_	10		No limit		μS
Max Gook input fall time	4CL		15		1	T	
			5	_	55	385	
Min clock pulse width	t <sub>W</sub>	_	10	_	25	150	ns
			15	_	16	120	
Min pulse width			5	_	60	385	
(RESET)	twH	_	10	_	26	150	ns
\			15	_	20	120	
Input capacitance	C <sub>IN</sub>	_			5	7.5	pF

# **Waveforms for Measurement of Dynamic Characteristics**

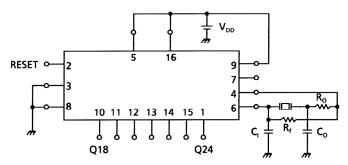


# **Application Circuit**

#### When CR Oscillation is Used as Time Reference



### When Crystal Oscillation is Used as the Time Reference

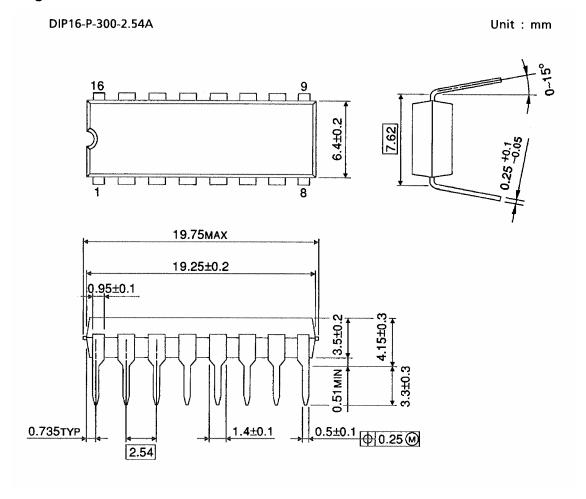


### **Typical Data**

X'tal (Hz)	C <sub>I</sub> , C <sub>O</sub> (pF)	R <sub>O</sub> (Ω)
32.768 k	23	500 k
100 k	60	100 k
1 M	45~50	100
4.194304 M	12~15	0

$$R_f=10\;M\Omega$$

# **Package Dimensions**



Weight: 1.00 g (typ.)

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20070701-EN GENERAL

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